

# 1-Mbit (64 K x 16) Static RAM

#### **Features**

- Temperature ranges
  □ Industrial: -40 °C to 85 °C
  □ Automotive-A: -40 °C to 85 °C
- Pin-and function-compatible with CY7C1021CV33
- High speed
  □ t<sub>AA</sub> = 10 ns
- Low active power
  □ I<sub>CC</sub> = 60 mA @ 10 ns
- Low CMOS standby power
  □ I<sub>SB2</sub> = 3 mA
- 2.0 V data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Independent control of upper and lower bits
- Available in Pb-free 44-pin 400-Mil wide molded SOJ, 44-pin TSOP II and 48-ball VFBGA packages

# Functional Description[1]

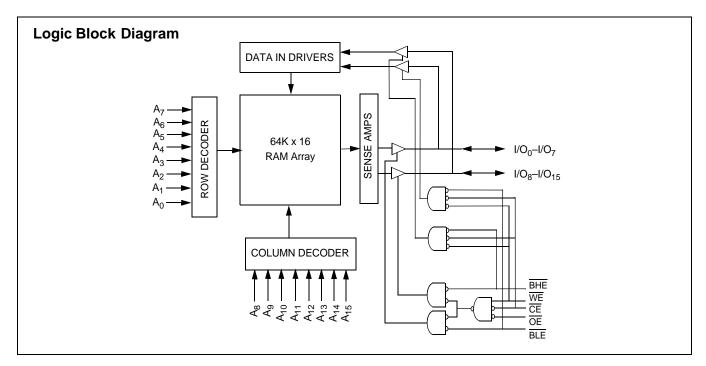
The CY7C1021DV33 is a high-performance CMOS static RAM organized as 65,536 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

Writing to the device is accomplished by taking Chip Enable ( $\overline{\text{CE}}$ ) and Write Enable (WE) inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O $_0$  through I/O $_7$ ), is written into the location specified on the address pins (A $_0$  through A $_{15}$ ). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O $_8$  through I/O $_{15}$ ) is written into the location specified on the address pins (A $_0$  through A $_{15}$ ).

Reading from the device is accomplished by taking Chip Enable ( $\overline{\text{CE}}$ ) and Output Enable ( $\overline{\text{OE}}$ ) LOW while forcing the Write Enable ( $\overline{\text{WE}}$ ) HIGH. If Byte Low Enable ( $\overline{\text{BLE}}$ ) is LOW, then data from the memory location specified by the address pins will appear on I/O $_0$  to I/O $_7$ . If Byte High Enable ( $\overline{\text{BHE}}$ ) is LOW, then data from memory will appear on I/O $_8$  to I/O $_{15}$ . See the truth table at the end of this data sheet for a complete description of Read and Write modes.

The input/output pins (I/O $_0$  through I/O $_{15}$ ) are placed in a high-impedance state when the <u>device</u> is desel<u>ected</u> ( $\overline{\text{CE}}$  HIGH), the outputs <u>are disabled</u> ( $\overline{\text{OE}}$  HIGH), the BHE and BLE <u>are disabled</u> ( $\overline{\text{BHE}}$ , BLE HIGH), or during a Write operation ( $\overline{\text{CE}}$  LOW, and  $\overline{\text{WE}}$  LOW).

The CY7C1021DV33 is available in Pb-free 44-pin 400-Mil wide Molded SOJ, 44-pin TSOP II and 48-ball VFBGA packages.

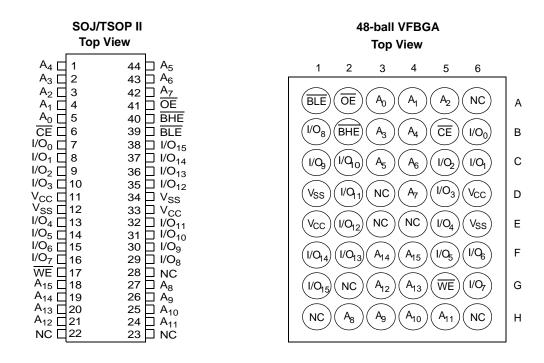




### **Selection Guide**

	-10 (Industrial/Automotive-A)	Unit
Maximum access time	10	ns
Maximum operating current	60	mA
Maximum CMOS standby current	3	mA

# Pin Configuration[1]



#### Notes

1. NC pins are not connected on the die.



# **Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage temperature ......-65 °C to +150 °C Ambient temperature with power applied .......55 °C to +125 °C Supply voltage on  $\rm V_{CC}$  to Relative  $\rm GND^{[2]}\,...-0.3~V$  to +4.6  $\rm V$ DC Voltage applied to outputs in high-Z  $\rm State^{[2]}$  .......-0.3 V to  $\rm V_{CC}\text{+}0.3~V$ DC input voltage<sup>[2]</sup>.....-0.3 V to V<sub>CC</sub>+0.3 V

Current into outputs (LOW)	20 mA
Static discharge voltage(per MIL-STD-883, method 3015)	> 2001 V
Latch-up current	>200 mA

# **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>	Speed
Industrial	−40 °C to +85°C	$3.3 \text{ V} \pm 0.3 \text{ V}$	10 ns
Automotive-A	−40 °C to +85°C		10 ns

# DC Electrical Characteristics Over the Operating Range

Doromotor	Decerintien	Test Conditions		–10 (Ind	I/Auto-A)	Unit
Parameter	Description	lest Conditions		Min.	Max.	Onit
V <sub>OH</sub>	Output HIGH voltage	$V_{CC} = Min., I_{OH} = -4.0 \text{ mA}$		2.4		V
V <sub>OL</sub>	Output LOW voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA			0.4	V
V <sub>IH</sub>	Input HIGH voltage			2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW voltage <sup>[2]</sup>			-0.3	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \le V_1 \le V_{CC}$		-1	+1	μΑ
I <sub>OZ</sub>	Output leakage current	$GND \le V_1 \le V_{CC}$ , Output Disabl	ed	-1	+1	μА
I <sub>CC</sub>	V <sub>CC</sub> operating	V <sub>CC</sub> = Max.,	100 MHz		60	mA
	supply current	$I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$	83 MHz		55	mA
		I IWAX "RC	66 MHz		45	mA
			40 MHz		30	mA
I <sub>SB1</sub>	Automatic CE Power-Down Current —TTL Inputs	$\begin{aligned} &\text{Max. V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}} \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{f} = \text{f}_{\text{MAX}} \end{aligned}$			10	mA
I <sub>SB2</sub>	Automatic CE Power-Down Current —CMOS Inputs	Max. $V_{CC}$ , $\overline{CE} \ge V_{CC} - 0.3 \text{ V}$ , $V_{IN} \ge V_{CC} - 0.3 \text{ V}$ or $V_{IN} \le 0.3 \text{ V}$	V, f = 0		3	mA

# Capacitance<sup>[3]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input capacitance	$T_A = 25$ °C, $f = 1$ MHz, $V_{CC} = 3.3$ V	8	pF
C <sub>OUT</sub>	Output capacitance		8	pF

### Thermal Resistance[3]

Parameter	Description	Test Conditions	SOJ	TSOP II	VFBGA	Unit
$\Theta_{JA}$		Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	59.52	53.91	36	°C/W
$\Theta_{\sf JC}$	Thermal resistance (Junction to Case)		36.75	21.24	9	°C/W

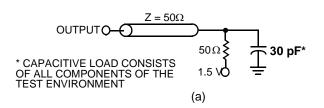
#### Notes

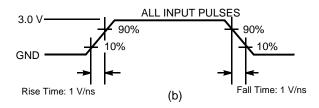
<sup>2.</sup> V<sub>IL</sub> (min.) = -2.0 V and V<sub>IH</sub>(max) = V<sub>CC</sub> + 1 V for pulse durations of less than 5 ns.

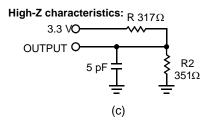
3. Tested initially and after any design or process changes that may affect these parameters.



### AC Test Loads and Waveforms[4]







#### Note

AC characteristics (except High-Z) are tested using the load conditions shown in Figure (a). High-Z characteristics are tested for all speeds using the test load shown in Figure (c).



# Switching Characteristics Over the Operating Range<sup>[5]</sup>

		-10 (Ind	I/Auto-A)	
Parameter	Description	Min.	Max.	Unit
Read Cycle		<u>'</u>	•	
t <sub>power</sub> <sup>[6]</sup>	V <sub>CC</sub> (typical) to the first access	100		μS
t <sub>RC</sub>	Read cycle time	10		ns
t <sub>AA</sub>	Address to data valid		10	ns
t <sub>OHA</sub>	Data hold from address change	3		ns
t <sub>ACE</sub>	CE LOW to data valid		10	ns
t <sub>DOE</sub>	OE LOW to data valid		5	ns
t <sub>LZOE</sub>	OE LOW to low-Z <sup>[8]</sup>	0		ns
t <sub>HZOE</sub>	OE HIGH to high-Z <sup>[7, 8]</sup>		5	ns
t <sub>LZCE</sub>	CE LOW to low-Z <sup>[8]</sup>	3		ns
t <sub>HZCE</sub> CE HIGH to high-Z <sup>[7, 8]</sup>			5	ns
t <sub>PU</sub> <sup>[9]</sup>	CE LOW to power-up	0		ns
t <sub>PD</sub> <sup>[9]</sup>	CE HIGH to power-down		10	ns
t <sub>DBE</sub>	Byte Enable to data valid		5	ns
t <sub>LZBE</sub>	Byte Enable to low-Z	0		ns
t <sub>HZBE</sub>	Byte Disable to high-Z		6	ns
Write Cycle <sup>[10]</sup>			•	
t <sub>WC</sub>	Write cycle time	10		ns
t <sub>SCE</sub>	CE LOW to write end	8		ns
t <sub>AW</sub>	Address set-up to write end	8		ns
t <sub>HA</sub>	Address hold from write end	0		ns
t <sub>SA</sub>	Address set-up to write start	0		ns
t <sub>PWE</sub>	WE pulse width	7		ns
t <sub>SD</sub>	Data set-up to write end	5		ns
t <sub>HD</sub>	Data hold from write end	0		ns
t <sub>LZWE</sub>	WE HIGH to low-Z <sup>[8]</sup>	3		ns
t <sub>HZWE</sub>	WE LOW to high-Z <sup>[7, 8]</sup>		5	ns
t <sub>BW</sub>	Byte enable to end of write	7		ns

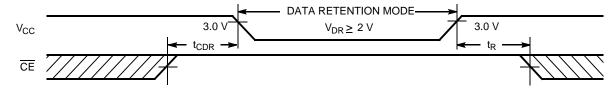
- Notes
   Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.
   tpower gives the minimum amount of time that the power supply should be at typical V<sub>CC</sub> values until the first memory access can be performed.
   th\_IZOE, th\_IZDE, th\_IZDE, th\_IZDE, and th\_IZWE are specified with a load capacitance of 5 pF as in (c) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.
   At any given temperature and voltage condition, th\_IZCE is less than th\_IZCE, th\_IZOE, and th\_IZWE is less than th\_IZCE, and the IZCE, a



# Data Retention Characteristics Over the Operating Range

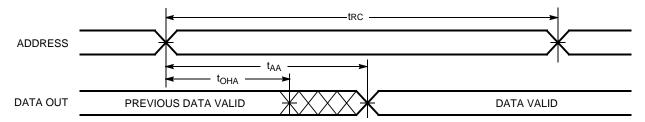
Parameter	Description	Conditions	Min.	Max.	Unit
$V_{DR}$	V <sub>CC</sub> for data retention		2		V
I <sub>CCDR</sub>	Data retention current	$ \begin{vmatrix} V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V}, \\ V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V} \end{vmatrix}                                  $		3	mA
t <sub>CDR</sub> <sup>[3]</sup>	Chip deselect to data retention time		0		ns
t <sub>R</sub> <sup>[11]</sup>	Operation recovery time		t <sub>RC</sub>		ns

### **Data Retention Waveform**

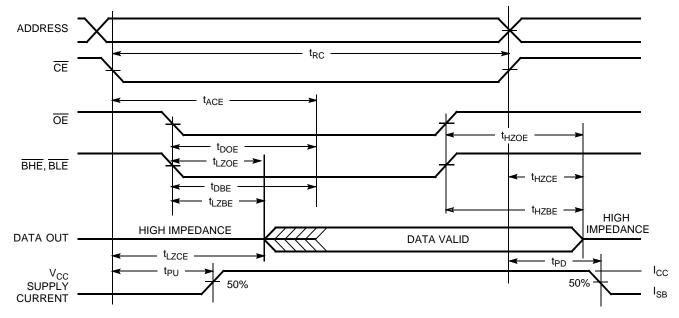


# **Switching Waveforms**

# Read Cycle No. 1 (Address Transition Controlled)[12, 13]



# Read Cycle No. 2 (OE Controlled)[13, 14]



#### Notes

- 11. Full device operation requires lin<u>ear V<sub>CC</sub> ramp</u> from V<sub>DR</sub> to V<sub>CC(min.)</sub> ≥ 50 μs or stable at V<sub>CC(min.)</sub> ≥ 50 μs.

  12. Device is continuously selected. OE, CE, BHE and/or BLE = V<sub>IL</sub>.

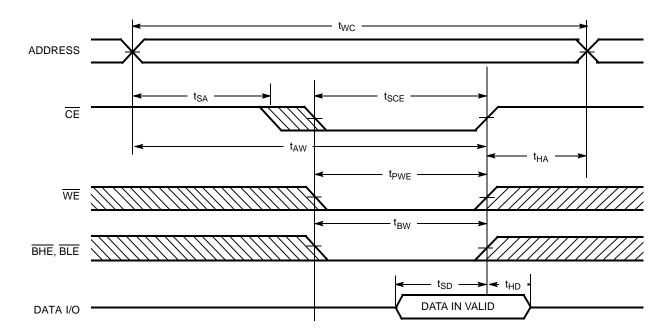
  13. WE is HIGH for Read cycle.

  14. Address valid prior to or coincident with CE transition LOW.

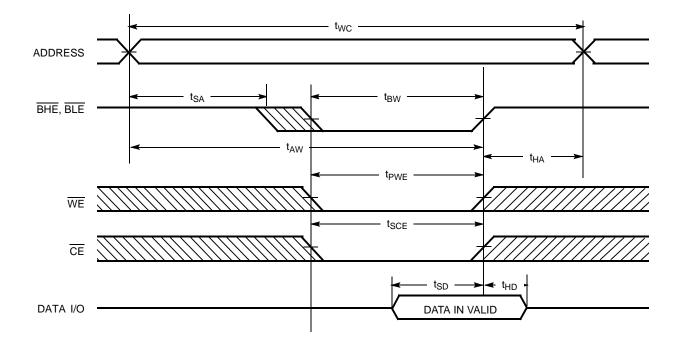


# **Switching Waveforms** (continued)

# Write Cycle No. 1 (CE Controlled)[15, 16]



# Write Cycle No. 2 (BLE or BHE Controlled)



### Notes

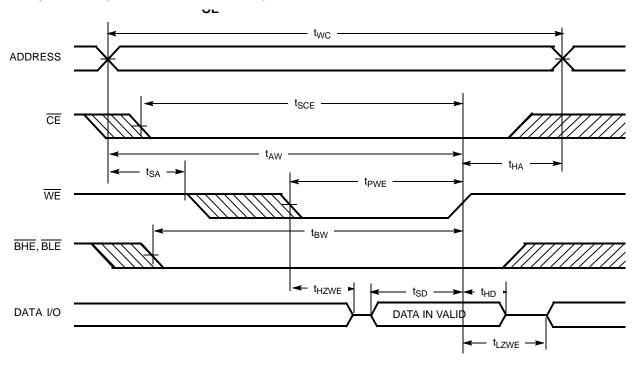
<sup>15.</sup> Data I/O is high impedance if  $\overline{OE}$  or  $\overline{BHE}$  and/or  $\overline{BLE} = V_{IH}$ .

16. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high-impedance state.



# Switching Waveforms (continued)

# Write Cycle No. 3 (WE Controlled, OE LOW)



# **Truth Table**

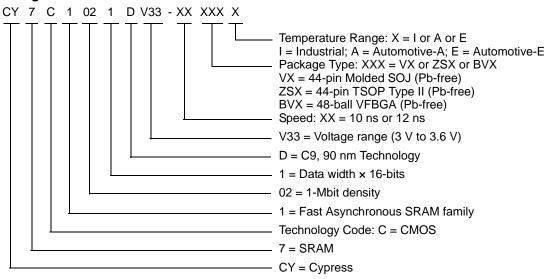
CE	ŌE	WE	BLE	BHE	I/O <sub>0</sub> –I/O <sub>7</sub>	I/O <sub>8</sub> –I/O <sub>15</sub>	Mode	Power
Н	Х	Х	Х	Х	High-Z	High-Z	Power-down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read – All bits	Active (I <sub>CC</sub> )
			L	Н	Data Out	High-Z	Read – Lower bits only	Active (I <sub>CC</sub> )
			Н	L	High-Z	Data Out	Read – Upper bits only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write – All bits	Active (I <sub>CC</sub> )
			L	Н	Data In	High-Z	Write – Lower bits only	Active (I <sub>CC</sub> )
			Н	L	High-Z	Data In	Write – Upper bits only	Active (I <sub>CC</sub> )
L	Н	Н	Х	Х	High-Z	High-Z	Selected, outputs disabled	Active (I <sub>CC</sub> )
L	Х	Х	Н	Н	High-Z	High-Z	Selected, outputs disabled	Active (I <sub>CC</sub> )



### **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1021DV33-10VXI	51-85082	44-pin (400-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1021DV33-10ZSXI	51-85087	44-pin TSOP Type II (Pb-free)	
	CY7C1021DV33-10BVXI	51-85150	48-ball VFBGA (Pb-free)	
10	CY7C1021DV33-10ZSXA	51-85087	44-pin TSOP Type II (Pb-free)	Automotive-A

### **Ordering Code Definitions**

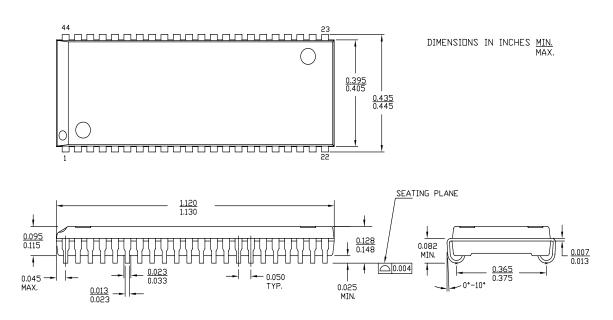


 $\label{thm:please contact your local Cypress sales representative for availability of these parts. \\$ 



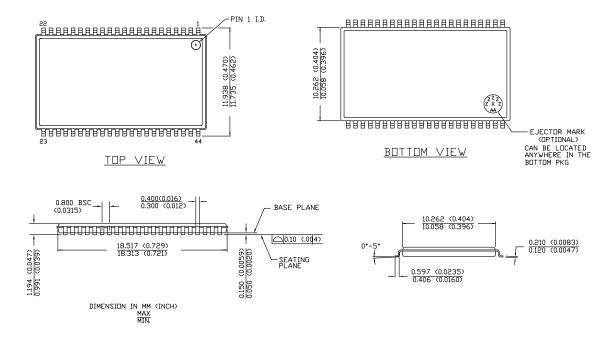
# **Package Diagrams**

Figure 1. 44-pin (400-Mil) Molded SOJ (51-85082)



51-85082 \*D

Figure 2. 44-pin Thin Small Outline Package Type II (51-85087)

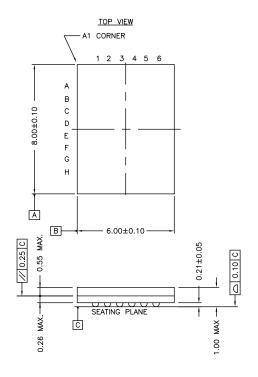


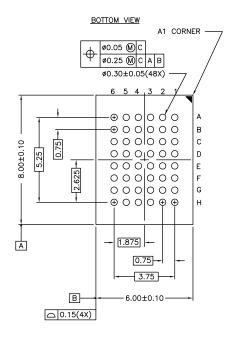
51-85087 \*D



# Package Diagrams (continued)

## Figure 3. 48-ball VFBGA (6 x 8 x 1 mm) (51-85150)





51-85150 \*G



# **Document History Page**

REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change		
**	201560	See ECN	SWI	Advance Information data sheet for C9 IPP		
*A	233693	See ECN	RKF	DC parameters are modified as per Eros (Spec # 01-02165). Pb-free Offering In Ordering Information		
*B	263769	See ECN	RKF	Added Data Retention Characteristics table Added T <sub>power</sub> Spec in Switching Characteristics table Shaded Ordering Information		
*C	307601	See ECN	RKF	Reduced Speed bins to -8 and -10 ns		
*D	520652	See ECN	VKN	Converted from Preliminary to Final Removed Commercial Operating range Removed 8 ns speed bin Added I <sub>CC</sub> values for the frequencies 83MHz, 66MHz and 40MHz Added Automotive Information Updated Thermal Resistance table Updated Ordering Information Table Changed Overshoot spec from V <sub>CC</sub> +2 V to V <sub>CC</sub> +1 V in footnote #4		
*E	2898399	03/24/2010	AJU	Updated Package Diagrams		
*F	3109897	12/14/2010	AJU	Added Ordering Code Definitions. Updated Package Diagrams.		
*G	3421856	10/25/2011	TAVA	Template Update Updated Features, Selection Guide, Operating Range, DC Electrical Chara teristics Over the Operating Range, Switching Characteristics Over the Operating Range <sup>[5]</sup> , Data Retention Characteristics Over the Operating Range Switching Waveforms, and Ordering Information Updated Package Diagrams		



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Document #: 38-05460 Rev. \*G Revised October 25, 2011 Page 13 of 13